


<b>Search Notes</b>  	<b>Application/Control No.</b>  10595157	<b>Applicant(s)/Patent Under Reexamination</b>  TAKENAKA ET AL.
	<b>Examiner</b>  John L Goff	<b>Art Unit</b>  1791

SEARCHED			
Class	Subclass	Date	Examiner
156	307.1,307.7	7/31/08	JLG

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout	7/31/08	JLG
Palm Inventor Search	7/31/08	JLG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner